



Search Notes 	Application/Control No. 10675543	Applicant(s)/Patent Under Reexamination HEIN ET AL.
	Examiner Chang, Joseph	Art Unit 2817


Notes	Date	Examiner
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	<p>Examiner</p> <p>Chang, Joseph</p>	<p>Art Unit</p> <p>2817</p>

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331	16, 44	10/15/06	JC

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